Modern electronic devices rely on stable DDR (double data rate) memory for fast, reliable operation. A shortened time to market, however, often limits the amount of product testing that you can perform. Microprocessor-based products released with unstable memory may experience only intermittent failures, but even those can lead to a costly recall. To minimize that risk, you can follow a comprehensive memory tuning and testing process that you can verify with an oscilloscope or logic analyzer.

Tuning is part of configuring a computer system’s DDR memory. Device-specific tuning will match a DDR memory device’s timing parameters with the configuration registers in the DDR memory controller’s CPU. Data sheets for DDR devices specify the timing required for proper operation, listed as fractions of a second. You must convert these timing parameters to clock cycles before you can program them into a memory controller. For this conversion, you should write some high-level DDR memory configuration software that will accept the standard timing data from a data sheet and convert it into processor clocks for low-level DDR memory drivers.

The next step of the tuning process will vary depending on your product’s CPU. Many CPUs let the user tune DDR memory parameters such as signal termination and read/write delays that may be specific to a particular board layout. The user manual for a DDR memory controller will specify any tuning capability that it provides.

**Read/write delays**
When included as part of the DDR memory controller, modified read delays or write delays can lead to the most stable system. A product may have several read/write delay values for which the DDR memory device will work—a window of operability. You should test those delay windows under a range of operating conditions, such as varying temperatures, to find the settings that will optimize DDR memory reliability.
Figure 1 depicts the timing of DDR memory write cycles with and without delays. You may need to add delays because the strobe and data transfer will shift in time relative to the DDR memory clock (not shown in Figure 1). In some cases, the read/write delay tuning and adjustment will occur every time a user powers on the product. Many designs, however, rely on this tuning process to occur during design only, with the released product using the optimal values that balance performance and reliability.

After you complete the initial tuning, you should put the product through several levels of validation testing. In some cases, testing will reveal the need for additional tuning. The key to effective DDR memory testing is to make your tests progressively more difficult, covering connectivity, memory retention, stress, and performance.

A best practice in DDR memory design is to manually verify that the PCB (printed-circuit board) traces are connected. You can use an oscilloscope, logic analyzer, or multimeter for this connection test. Once you complete this initial design check, software tests can verify the DDR memory address and data line connections for proper operation at the speed of the processor. An address bus test writes a base pattern and then a test pattern to all power-of-two offsets (0001h, 0002h, 0004h, etc.). Data bus tests use a “walking-ones-and-zeros” pattern that tests across the width of the data bus on a single memory word. These tests verify that no shorts exist to power or ground or between any data lines or any address lines.

### Walking ones

For a walking-ones pattern, your software, whether purchased or written in-house, must perform successive writes to the given address. First, the software sets the LSB (least-significant bit) to 1 and all other bits to 0. Next, the software sets the next LSB to 1 and all other bits to 0; and so on, until each bit has been set to 1 (Figure 2).

After you verify connectivity, you should run functional validation tests to ensure that all the memory cells in the DDR memory can retain the values written to them. Filling and verifying all the cells with their own address values as data can accomplish this task. Additionally, you should fill all the cells and verify that all the memory cells can store both ones and zeros. Use the one’s complement of the cells’ addresses to run this test.

Several advanced CPUs include software that performs DDR memory stress tests, which ensure that the memory can perform at your system’s full speed. Such processors can simulate an application-like environment. By running your functional tests with cache enabled, you will also force data bursts between the processor and DDR memory as cache lines get flushed and replaced. Running DMA (direct-memory access) loop tests while also receiving Ethernet packets via interrupts can cause multiple simultaneous DDR memory reads and writes that will stress the memory and ensure coherency.

Figure 3 illustrates the block-level interaction of the DDR memory with a system’s cache memory, DMA, and Ethernet controllers. Each line between the components represents data transfers from one logic component to the other. In the case of DMA, you can program multiple transfers to occur simultaneously across multiple channels. The actual number of channels is a feature of a particular microprocessor.

Knowing that your DDR memory is properly connected and won’t produce errors under stress isn’t always enough. You must also measure how well the DDR memory performs. Using a software test with optimized read and write routines, you can determine whether the performance and throughput of the DDR memory are fast enough to ensure that software running in your system will run properly. You must measure performance early in a product’s development to resolve any bottlenecks in the data path.

### Dedicated applications

When developing software for tuning and testing DDR memory, you should implement the needed routines in a dedicated software application. Although you could develop JTAG tests for tuning and testing—a fairly simple process—you wouldn’t be able to operate the DDR memory at a processor’s full speed, which is a major testing limitation. Building DDR memory tests on top of an application is also a tempting option, but this approach for memory testing makes it difficult to find a problem’s root cause because of the many layers of software that test routines use.

You should develop modular DDR memory test software (Figure 4) so you can reuse test routines across departments throughout your organization. Design engineers can use the software for initial

![FIGURE 1](image1.jpg) **FIGURE 1.** Adding delay to a write cycle can improve performance and system stability.

![FIGURE 2](image2.jpg) **FIGURE 2.** A walking-ones data pattern ensures that no shorts exist across data lines.

![FIGURE 3](image3.jpg) **FIGURE 3.** During a test, DDR memory must interact with cache memory, DMA, and Ethernet controllers.
board verification. Test engineers can use the test routines to determine if a problem is related to hardware or software by using known-good tests. A known-good test contains no programming errors that would produce false results, such as identifying errors that don’t exist or missing errors that do exist.

Test engineers and manufacturing engineers can also use the test routines to verify data paths and general functionality.

Because the same software was used to validate the product’s design, there will be no need to rerun extensive stress or performance tests during manufacturing.

Modular software will also let you run the same routines in a POST (power-on self-test) application. If POST is required, it often needs to run quickly but have the ability to warn end users if a memory problem exists. Thus, you can use DDR memory test routines to uncover potential memory problems before they affect a system’s operation.

You can also use DDR memory test software on units that have failed in the field and have been returned for service. Memory-testing software can quickly pinpoint the root cause of the problem. Software that effectively validates a design initially should always be sufficient to determine problems on returned products. Field application engineers can use the same set of software tests to validate memory during customer visits and find potential problems before the customer knows that a problem exists.

Stable DDR memory can often be the key to a company’s success. Using a design process that includes proper tuning of DDR memory, followed by thorough memory validation testing will, at least, assure you that you have a stable main platform.

Additionally, if you create a DDR memory tuning and testing process using a modular software approach, you can reuse the process throughout your organization. Not only will the reuse save money, it will help your company to build reliable products and correct memory faults—whether found during development, in production, or in the field. Stable memory can’t guarantee that your product will be a success, but neglecting to spend time ensuring that your product has stable memory will nearly always lead to failure. T&MW

**Andrew Fish** is a senior contributor to Kozio’s library-based functional tests. He joined Kozio in 2004 and has more than 11 years of embedded programming experience. Fish has developed advanced test capabilities and support for numerous microprocessors and peripheral technologies. He holds a BSEE from Marquette University.